

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/693,058	CHO ET AL.	
Examiner	Art Unit	
ThiO Io	2613	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST image and keyword search in US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT and IBM_TDB (see EAST search history attached)	7/18/2007	TL			